

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No.: CV-0042

Previous Docket No. CC-0652

JOHN MOON ET AL

Group No.: 1743

Serial No.: 10/661,836

Confirmation: 8531

Filed: September 12, 2003

Title: Method and Apparatus for Aligning Microbeads in order to Interrogate the same

Commissioner of Patents and Trademarks

P.O. Box 1450

Alexandria, VA 22313

## INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants submit herewith references in accordance with 37 CFR 1.56 and 37 CFR 1.97(b)(3) which is before the mailing date of a first Office action on the merits.

Additionally, each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application. A copy of the communication from the foreign patent office, i.e. the International Search Report, is also enclosed.

Also enclosed is form PTO1449 listing the cited reference.

Please charge any additional fees or credit overpayment to Deposit Account No. 50-2994, Order No. CV-0042.

Respectfully submitted,

JOHN MOON ET AL

Gerald L. DePardo

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Form PTQ-1449 (Rev. 8-89)					-			Commerce ark Office	Attorney Doc CC-0652	(CV-0042) Serial No. 10/661,836			/661,836
Information Disclosure Citation									Applicant:  John Moon et al				
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in conformance and not considered. Include copy of the form with next communication to applicant.